L-Number	Hits	Search Text	DB	Time stamp
–	5	039404.ap.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/29 15:01
–	4	039484.ap.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/07 12:04
–	28	method near4 circuit adj simulation.clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/07 12:08
–	0	apparatus near6 computer adj simulation near6 circuit.clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/07 12:09
–	162	computer adj system near6 simulation.clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/07 12:10
–	8	(US-20030154064-$ or US-20030154065-$ or US-20030154447-$ or US-20030154453-$ or US-20030154454-$ or US-20030163277-$ or US-20030163510-$ or US-20030164239-$).did.	US-PGPUB	2003/09/07 12:42
–	0	simulating.clm. and apparatus.clm. and design.clm.	USPAT; US-PGPUB	2003/09/07 12:43
–	840	simulating near6 circuit.clm.	USPAT; US-PGPUB	2003/09/07 12:44
–	7	(US-20030154453-$ or US-20030154454-$ or US-20030163277-$ or US-20030163510-$ or US-20030154447-$ or US-20030154065-$ or US-20030154064-$).did.	US-PGPUB	2004/05/19 11:21
–	1136	((703/13) or (703/14)).CCLS.	USPAT; US-PGPUB	2004/05/19 13:54
–	42	(((703/13) or (703/14)).CCLS.) and method near6 capacitance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/19 14:16
–	0	(((703/13) or (703/14)).CCLS.) and method near6 capacitance and simulat$3 near6 design adj structure	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/19 14:21
–	0	method near6 capacitance near6 simulat$3 and simul$3 near6 design adj structure and parasitic adj capacitance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/19 15:16
–	0	method near6 capacitance near6 simulat$3 and simul$3 near6 design adj structure	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/19 15:16
–	1814	circuit near3 simulat$3.clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/19 15:16
–	95	circuit near3 simulat$3.clm. and method near6 (capacitance capacitor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/19 15:35

	34	circuit near3 simulat$3.clm. and method near6 (capacitance capacitor) and design near6 simulat$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/19 17:26
	15	gallia.in. near6 james.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/19 17:29
	5	gallia.in. near6 james.in. and design$3 and capacitance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/19 17:31
	19	(design$3 determin$3) near3 capacitance near20 (circuit near2 simulat$3).ti,ab,clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/19 17:33
	7	(design$3 determin$3) near3 capacitance near20 (circuit near2 simulat$3).ti,ab,clm. and parasitic.ti,ab,clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/20 10:38
	1137	((703/13) or (703/14)).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/20 10:38
	58	(((703/13) or (703/14)).CCLS.) and circuit adj simulati$2 and design and capacitance and parasitic	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/20 10:51
	0	(((703/13) or (703/14)).CCLS.) and circuit adj simulati$2 and design adj structure and test adj structure and capacitance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/20 10:52
	0	(((703/13) or (703/14)).CCLS.) and circuit adj simulati$2 and design adj structure and test adj structure	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/20 10:52
	158	(((703/13) or (703/14)).CCLS.) and circuit adj simulati$2 and design and test	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/20 10:52
	8	(((703/13) or (703/14)).CCLS.) and circuit adj simulati$2 and design and test and capacitance and parasitic adj capacitance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/20 11:10
	4	(((703/13) or (703/14)).CCLS.) and circuit adj simulati$2 and design and test and capacitance and (wire interconnect) adj capacitance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/20 11:18
	0	estimat$3 near2 parasitic adj capacitance near8 test	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/20 11:19
	37	estimat$3 near2 parasitic adj capacitance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/20 11:19

—		1	estimat$3 near2 parasitic adj capacitance and test adj structure	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/20 11:20
—		0	estimat$3 near2 parasitic adj capacitance and test adj (device transistor capacitor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/20 11:22
—		12	estimat$3 near2 parasitic adj capacitance and simulation	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/20 14:10
—		2	("6243653").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/20 15:35
—		6	extraction near4 parasitic adj capacitance.ti,ab,clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/20 15:36
—		4	extraction near4 parasitic adj capacitance.ti,ab,clm. and circuit near2 simulat$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/20 15:36
—		0	6243653.pn. and physical$2 near3 test$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/21 10:40
—		0	6243653.pn. and test$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/21 10:40
—		0	(("6243653").PN.) and physical$2 and test$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/21 10:41
—		0	(("6243653").PN.) and test$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/21 10:41
—		2	("6243653").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/21 10:42
—		0	physical$2 near2 test$3 and extract$3 near3 parasitic adj capaciance and simulat$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/21 10:43
—		1	physical$2 near2 test$3 and extract$3 near3 parasitic adj capacitance and simulat$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/21 10:53
—		2	("5706206").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/21 11:10

–		6	capacitance near3 test$3 and capacitance near3 design$3 and parasitic adj capacitance near4 test$3 near6 design$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/21 11:12
–		6	capacitance near3 (physical test$3) and capacitance near3 (simulat$3 design$3) and parasitic adj capacitance near4 test$3 near6 design$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/21 11:13
–		45	capacitance near3 (physical test$3) and capacitance near3 (simulat$3 design$3) and parasitic adj capacitance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/21 11:13
–		56	(extracting extraction) near4 (parasitic adj capacitance)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/24 19:39
–		5	(extracting extraction) near4 (parasitic adj capacitance) and subtract$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/24 19:48
–		2	(extracting extraction) near4 (parasitic adj capacitance) and subtract$3 and sum	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/24 19:56
–		5	(extracting extraction) near4 (parasitic adj capacitance) and subtract$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/24 19:56
–		6	raphael and parasitic adj capacitance and three adj dimensional	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/25 14:34
–		126	cmos and gate adj contact and parasitic adj capacitance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/25 14:35
–		84	width near2 gate and parasitic adj capacitance and (extracting extraction)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 10:42
–		2	width near2 gate and parasitic adj capacitance near3 (extracting extraction)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 12:57
–		0	raphael.ti,ab,clm. and boundary adj conditions	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 12:57
–		3	raphael and boundary adj conditions and parasitic adj capacitance.ti,ab,clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 12:57
–		2	overlap near3 gate and parasitic adj capacitance and raphael	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/27 13:17

–		3473	capacitance near3 drain near4 source	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/27 16:40
–		108	capacitance near3 drain near4 source and parasitic adj capacitance and simulation	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/27 16:41
–		102	capacitance near3 drain near3 source and parasitic adj capacitance and simulation	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/27 17:28
–		1	calibration adj structure and parasitic adj capacitance and test adj structure and simulation	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/27 17:29
–		2	calibration and parasitic adj capacitance and test adj structure and simulation	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/27 17:31
–		2	calibrati$2 and parasitic adj capacitance and test adj structure and simulation	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/27 17:31
–		2	6449754.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/28 09:12
–		19722	apparatus near3 simulating near3 integrated circuit near3 operation.clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/28 15:18
–		0	apparatus near3 simulating near3 integrated adj circuit near3 operation.clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/28 15:18
–		0	apparatus near6 simulating near6 integrated adj circuit near6 operation.clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/28 15:22
–		0	apparatus near6 simulating near6 integrated adj circuit near6 operation.ti,ab,clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/28 15:23
–		1	apparatus near6 simulati$2 near6 integrated adj circuit near6 operation.ti,ab,clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/28 15:24
–		4964	apparatus near6 simulati$2.ti,ab,clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/28 15:24
–		4087	apparatus near3 simulati$2.ti,ab,clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/28 15:25

–	383	apparatus near3 simulati$2 near6 (semiconductor integrated circuit).ti,ab,clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/28 15:26
–	4	039484.ap.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/28 19:16
–	2	("6169302").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/29 18:06
–	62	apparatus near3 simulating near3 circuit.ti,ab,clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/29 18:06
–	7	apparatus near3 simulating near3 circuit.ti,ab,clm. and computer.ti,ab,clm. and processor.ti,ab,clm. and memory.ti,ab,clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/29 18:07